

EV372467626

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application Serial No. 09/388,063
Filing Date August 30, 1999
Inventor Vishnu K. Agarwal, et al.
Assignee Micron Technology, Inc.
Group Art Unit 2815
Examiner J. Fenty
Attorney's Docket No. MI22-1196
Title: Capacitors Having a Capacitor Dielectric Layer Comprising a Metal Oxide Having
Multiple Different Metals Bonded with Oxygen.

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

References -- See Attached Form PTO-1449

In compliance with 37 C.F.R. §§ 1.56, 1.97 and 1.98, your attention is directed to the references listed on the attached Form PTO-1449. No admission is made regarding whether all the submitted references are prior art.


09/22/2004 HMEKONEN 00000074 09388063

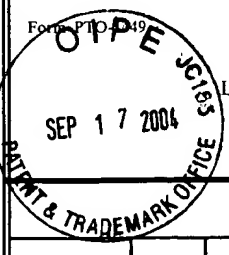
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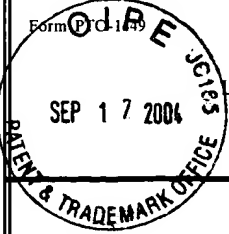
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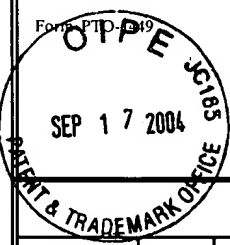
Respectfully Submitted:

Dated: 9-17-04

By: 
D. Brent Kenady
Reg. No. 40,045

Form PTO-419 		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-1196		SERIAL NO. 09/388,063	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Vishnu K. Agarwal et al.			
				FILING DATE Aug. 30, 1999		GROUP 2815	
U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA	4,261,698	04/81	Carr et al.			
	AB	4,691,662	09/87	Roppel et al.			
	AC	5,261,961	11/93	Takasu et al.			
	AD	5,270,241	12/93	Dennison et al.			
	AE	5,312,783	05/94	Takasaki et al.			
	AF	5,392,189	02/95	Fazan et al.			
	AG	5,395,771	03/95	Nakato			
	AH	5,468,687	11/95	Carl et al.			
	AI	5,525,156	06/96	Manada et al.			
	AJ	5,614,018	03/97	Azuma et al.			
	AK	5,656,329	08/97	Hampden-Smith			
	AL	5,663,089	09/97	Tomozawa et al.			
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
							Yes No
	AM	EP 0 030 798	06/81	EPO - Hughes			N/A
	AN	GB 2 194 555 A	03/88	UK - Nippon			N/A
	AO	EP 0 306 069 A2	03/89	EPO - Phillips			N/A
	AP	EP 0 388 957 A2	09/90	EPO - NEC Corp			N/A
	AQ	JP 2250970	10/90	Japan - NEC Corp			ABS
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	AR		Aoyama et al., "Leakage Current Mechanism of Amorphous and Polycrystalline Ta ₂ O ₅ Films Grown by chemical Vapor Deposition,"				
			1995, pages 977-983.				
	AS		Stemmer et al., "Accommodation of nonstoichiometry in (100) fiber-textured ... thin films grown by chemical vapor deposition,"				
			©1999 American Institute of Physics, pages 2432-2434.				
	AT		Streiffer et al., "Ferroelectricity in thin films: The dielectric response of fiber-textured ... thin films grown by chemical vapor deposition,"				
			©1999 American Institute of Physics, pages 45654575.				
EXAMINERs				DATE CONSIDERED			
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

Form PTO-1199 		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-1196		SERIAL NO. 09/388,063		
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Vishnu K. Agarwal et al.				
				FILING DATE Aug. 30, 1999		GROUP 2815		
U.S. PATENT DOCUMENTS								
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
	AA	5,702,562	12/97	Wakahara				
	AB	5,719,417	02/98	Roeder et al.				
	AC	5,723,361	03/98	Azuma et al.				
	AD	5,736,759	04/98	Haushalter				
	AE	5,976,990	11/99	Mercaldi et al.				
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	AG	6,101,085	08/00	Kawahara et al.				
	AH	6,215,650	04/01	Gnade et al.				
	AI	6,258,654	07/01	Gocho				
	AJ	6,287,935	09/01	Coursey				
	AK	6,325,017 B1	12/01	DeBoer et al.				
	AL	6,335,049 B1	01/02	Basceri				
FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AM	JP 04-24922	01/92	Japan - Mitsubishi			X	
	AN	JP 04-115533	04/92	Japan - Oki Elec.			X	
	AO	JP 04-180566	06/92	Japan - Mitsushita			ABS	
	AP	JP 08-060347	03/96	Japan - Fujitsu			X	
	AQ	EP 0 810 666 A1	12/97	EPO - Oki Electric			N/A	
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
	AR							
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	AT							
EXAMINER				DATE CONSIDERED				
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Form PTO-609 		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-1196		SERIAL NO. 09/388,063		
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Vishnu K. Agarwal et al.		FILING DATE Aug. 30, 1999		
				GROUP 2815				
U.S. PATENT DOCUMENTS								
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
	AA	6,566,147 B2	05/03	Basceri et al.				
	AB							
	AC							
	AD							
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	AI							
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	AK							
	AL							
FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AM	EP 0 892 426 A2	01/99	EPO - Ramtron			N/A	
	AN	JP 2000091333	03/00	Japan			X	
	AO	WO 01/16395	03/01	WIPO - Micron			N/A	
	AP							
	AQ							
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
	AR							
	AS							
	AT							
EXAMINER				DATE CONSIDERED				
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.								